

Issue Classification				Application/Control No.		Applicant(s)/Patent under Reexamination	
				10/747,644		DEMIR ET AL.	
				Examiner		Art Unit	
				Eva Yi Zheng		2611	

ISSUE CLASSIFICATION				
ORIGINAL		CROSS REFERENCE(S)		
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)	
375	322	375	316	324
INTERNATIONAL CLASSIFICATION		455	209	130
H	0	3	D	3/00
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 Eva Zheng 4/24/07 (Assistant Examiner) (Date)			 CHIEH M. FAN SUPERVISORY PATENT EXAMINER (Primary Examiner) (Date) 4/27/07	
			Total Claims Allowed: 31 O.G. Print Claim(s) 1	
			O.G. Print Fig. 2	

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original
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4	5	35	65	95	125	155	185
5	6	36	66	96	126	156	186
	7	37	67	97	127	157	187
6	8	38	68	98	128	158	188
7	9	39	69	99	129	159	189
8	10	40	70	100	130	160	190
9	11	41	71	101	131	161	191
10	12	42	72	102	132	162	192
11	13	43	73	103	133	163	193
	14	44	74	104	134	164	194
12	15	45	75	105	135	165	195
13	16	46	76	106	136	166	196
14	17	47	77	107	137	167	197
15	18	48	78	108	138	168	198
	19	49	79	109	139	169	199
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21	25	55	85	115	145	175	205
	26	56	86	116	146	176	206
22	27	57	87	117	147	177	207
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